



TEST REPORT

Report No.: HK1901210164E

FCC PART 15 SUBPART C 15.247

Test report
On Behalf of
SUNVALLEYTEK INTERNATIONAL, INC.
For
4K UST Laser Projector

Model No.:VA-LT002

FCC ID: 2AFDGVA-LT002

Prepared for: SUNVALLEYTEK INTERNATIONAL, INC.

46724 Lakeview Blvd, Fremont, CA 94538

Prepared By: Shenzhen HUAK Testing Technology Co., Ltd.

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Date of Test: Jan. 15, 2019 to Jan. 21, 2019

Date of Report: Jan. 21, 2019
Report Number: HK1901210164E

Page 2 of 58 Report No.: HK1901210164E

TEST RESULT CERTIFICATION

Applicant's name	SUNVALLE	YTEK INTERNATIONAL, INC.		
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Manufacture's Na	me Shenzhen N	learbyExpress Technology Development Company Limited		
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		Shenzhen NearbyExpress Technology Development Company Limited		
Address	333 Bulong District, She	Road, Jialianda Industrial Park, Building 1,Bantian, Longgang nzhen, China		
Product descripti				
Trade Mark:	VAVA			
Product name	4K UST Las	er Projector		
Model and/or type	reference VA-LT002			
Standards	47 CFR FC	C Part 15 Subpart C 15.247		
liability for damage placement and cor	s resulting from the reade	gy Co., Ltd. takes no responsibility for and will not assume er's interpretation of the reproduced material due to its		
Date (s) of performa	ance of tests:	Jan. 15, 2019 to Jan. 21, 2019		
Date of Issue	:	Jan. 21, 2019		
Test Result	:	Pass		
	Testing Engineer :	Gary Qian)		
	Technical Manager :	Edan Hu		

Authorized Signatory:

(Jason Zhou)

(Eden Hu)



TABLE OF CONTENTS

Report No.: HK1901210164E

1.1. TEST STANDARDS	1.	SUN	/MARY	4
1.3. TEST FACILITY		1.1.	TEST STANDARDS	4
1.4. STATEMENT OF THE MICASUREMENT UNCERTAINTY 2.2. GENERAL INFORMATION		1.2.	TEST DESCRIPTION	4
2. GENERAL INFORMATION. 2.1. ENVIRONMENTAL CONDITIONS. 2.1. ENVIRONMENTAL CONDITIONS. 2.2. GENERAL DESCRIPTION OF EUT 2.3. DESCRIPTION OF TEST MODES AND TEST FREQUENCY. 2.4. RELATED SUBMITTAL(S) / GRANT (S). 2.5. MODIFICATIONS. 2.6. RECEIVER INDUIT BANDWIDTH. 2.7. EXAMPLE OF A HOPPIOR SEQUENCE IN DATA MODE. 2.8. EQUALLY AVERAGE USE OF FREQUENCIES AND BEHAVIOUR. 2.9. EQUIPMENT USED. 3.1. MEASUREMENT PROCEDURE. 3.1. MEASUREMENT PROCEDURE. 3.1. MEASUREMENT PROCEDURE. 4.2 TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION). 3.3. LIMITS AND MEASUREMENT RESULT. 4.1. MEASUREMENT PROCEDURE. 4.1. MEASUREMENT PROCEDURE. 4.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION). 4.3. LIMITS AND MEASUREMENT RESULTS. 5. CONDUCTED SPURIOUS EMISSION. 5.1. MEASUREMENT PROCEDURE. 5.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION). 2.5.1. MEASUREMENT PROCEDURE. 3.6. RADIATED FROM SUBMISSION. 3.6. MEASUREMENT PROCEDURE. 4.7. LIMITS AND MEASUREMENT RESULTS. 4.7. LIMITS AND MEASUREMENT RESULTS. 5.1. LIMITS AND MEASUREMENT RESULTS. 5.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION). 2.5. LIMITS AND MEASUREMENT RESULTS. 4. THE MEASUREMENT PROCEDURE. 4. THE MEASUREMENT PROCEDURE OF MINISSION TEST. 5. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION). 5. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION). 5. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION). 5. TES		1.3.	TEST FACILITY	5
2.1. ENVIRONMENTAL CONDITIONS. 2.2. GENERAL DESCRIPTION OF EST MODES AND TEST FREQUENCY. 2.4. RELATED SUBMITTAL (S) / GRANT (S). 2.5. MODIFICATIONS. 2.6. RECEIVER INPUT BANDWIDTH. 2.7. EXAMPLE OF A HOPPING SEQUENCE IN DATA MODE. 2.8. EQUALITY AVERAGE USE OF FREQUENCIES AND BEHAVIOUR. 2.9. EQUIPMENT USED. 3.1. MEASUREMENT PROCEDURE. 3.1. MEASUREMENT PROCEDURE. 3.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION). 3.3. LIMITS AND MEASUREMENT RESULT. 4.1. MEASUREMENT PROCEDURE. 4.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION). 4.1. MEASUREMENT PROCEDURE. 4.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION). 4.3. LIMITS AND MEASUREMENT RESULTS. 5.1. MEASUREMENT PROCEDURE. 2.5. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION). 4.5. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION). 5.1. MEASUREMENT PROCEDURE. 5.2. TEST SET-UP. (BLOCK DIAGRAM OF CONFIGURATION). 6.1. MEASUREMENT PROCEDURE. 6.2. </td <td></td> <td>1.4.</td> <td>STATEMENT OF THE MEASUREMENT UNCERTAINTY</td> <td>5</td>		1.4.	STATEMENT OF THE MEASUREMENT UNCERTAINTY	5
2.2. GENERAL DESCRIPTION OF ELT 2.3. DESCRIPTION OF TEST MODE AND TEST FREQUENCY. 2.4. RELATED SUBMITITAL(S) / GRANT (S). 2.5. MODIFICATIONS. 2.6. RECEIVER INPUT BANDWIDTH 2.7. EXAMPLE OF A HOPPING SEQUENCE IN DATA MODE. 2.8. EQUALIT AVERAGE USE OF FREQUENCIES AND BEHAVIOUR 2.9. EQUIPMENT USED. 3.1. MEASUREMENT PROCEDURE. 3.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION). 3.3. LIMITS AND MEASUREMENT RESULT. 4.1. MEASUREMENT PROCEDURE. 4.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION). 4.3. LIMITS AND MEASUREMENT RESULTS. 5. CONDUCTED SPURICUS EMISSION. 5.1. MEASUREMENT PROCEDURE. 5.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION). 5.3. LIMITS AND MEASUREMENT RESULT. 6. RADIATED EMISSION. 6.1. MEASUREMENT PROCEDURE. 6.2. TEST SETUP. 6.3. LIMITS AND MEASUREMENT RESULT. 7.1. LIMITS OF LINE CONDUCTED EMISSION TEST.	2.	GEN		
2.3. DESCRIPTION OF TEST MODES AND TEST FREQUENCY 2.4. RELATED SUBMITTAL(S) / GRANT (S)				
2.4. RELATED SUBMITTAL(S) / GRANT (S) 2.5. MODIFICATIONS 2.6. Receiver Input Bandwindth 2.7. EXAMPLE OF A HOPPING SEQUENCE IN DATA MODE 2.8. EQUALITY AVERAGE USE OF FREQUENCIES AND BEHAVIOUR 2.9. EQUIPMENT USED 3. PEAK OUTPUT POWER 3.1. MEASUREMENT PROCEDURE 3.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION) 4.1. MEASUREMENT PROCEDURE 4.1. 1 MEASUREMENT PROCEDURE 4.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION) 4.3. LIMITS AND MEASUREMENT RESULT 5. CONDUCTED SPURIOUS EMISSION 5.1. MEASUREMENT PROCEDURE 5.1. MEASUREMENT PROCEDURE 5.1. MEASUREMENT PROCEDURE 6.1. MEASUREMENT PROCEDURE <td< td=""><td></td><td></td><td></td><td></td></td<>				
2.5. MODIFICATIONS. 2.6. RECEIVER INPUT BANDWIDTH 2.7. EXAMPLE OF A HOPPING SEQUENCE IN DATA MODE 2.8. EQUALLY AVERAGE USE OF FREQUENCIES AND BEHAVIOUR 2.9. EQUIPMENT USED. 3.1. MEASUREMENT PROCEDURE. 3.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION) 3.3. LIMITS AND MEASUREMENT RESULT 4. 200B BANDWIDTH 4.1. MEASUREMENT PROCEDURE. 4.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION) 4.3. LIMITS AND MEASUREMENT RESULTS 5. CONDUCTED SPURIOUS EMISSION 5.1. MEASUREMENT PROCEDURE. 5.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION) 5.3. LIMITS AND MEASUREMENT RESULT 5.3. LIMITS AND MEASUREMENT RESULT 5.3. LIMITS AND MEASUREMENT RESULT 6.1. MEASUREMENT PROCEDURE 6.2. TEST SETUP				
2.6. RECEIVER INPUT BANDWIDTH 2.7. EXAMPLE OF A HOPPING SEQUENCE IN DATA MODE 2.8. EQUALY AVERAGE USE OF FREQUENCIES AND BEHAVIOUR 2.9. EQUIPMENT USED 3. PEAK OUTPUT POWER. 3.1. MEASUBLEMENT PROCEDURE. 3.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION) 3.3. LIMITS AND MEASUREMENT RESULT 4.1. MEASUREMENT PROCEDURE. 4.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION) 4.3. LIMITS AND MEASUREMENT RESULT 4.1. MEASUREMENT PROCEDURE. 4.3. LIMITS AND MEASUREMENT RESULT 5. CONDUCTED SPURIOUS EMISSION 5.1. MEASUREMENT PROCEDURE. 5.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION) 5.3. LIMITS AND MEASUREMENT RESULT 5.3. LIMITS AND MEASUREMENT RESULT 6. RADIATED EMISSION 7. LIMITS AND MEASUREMENT RESULT 7. LIMITS OF LINE SUBJECT 7. LIMITS OF LINE OF LINE CONDUCTED EMISSION TEST 7. LINE CONDUCTED EMISSION				
2.7. EXAMPLE OF A HOPPING SEQUENCE IN DATA MODE. 2.8. EQUALY AVERAGE USE OF FREQUENCIES AND BEHAVIOUR. 2.9. EQUIPMENT USED. 3. PEAK OUTPUT POWER. 1 3.1. MEASUREMENT PROCEDURE. 11 3.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION). 11 3.3. LIMITS AND MEASUREMENT RESULT. 1. 4. 20DB BANDWIDTH 1. 4.1. MEASUREMENT PROCEDURE. 1. 4.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION). 1. 4.3. LIMITS AND MEASUREMENT RESULTS. 1. 5.1. MEASUREMENT PROCEDURE. 2. 5.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION). 2. 5.1. MEASUREMENT PROCEDURE. 2. 5.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION). 2. 5.3. LIMITS AND MEASUREMENT RESULT 2. 6. RADIATED EMISSION 3. 6.1. MEASUREMENT PROCEDURE. 3. 6.2. TEST SETUR. 3. 6.2. TEST SETUR. 3. 7.1. LIMITS OF LINE CONDUCTED EMISSION TEST. <td< td=""><td></td><td></td><td></td><td></td></td<>				
2.8. EQUALLY AVERAGE USE OF FREQUENCIES AND BEHAVIOUR 2.9. EQUIPMENT USED. 3.1. MEASUREMENT PROCEDURE. 3.1. MEASUREMENT PROCEDURE. 3.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION). 3.3. LIMITS AND MEASUREMENT RESULT. 4. 20DB BANDWIDTH				
2.9. EQUIPMENT USED			·	
3.1 Measurement Procedure 11 3.1 Measurement Procedure 12 3.2 Test Set-Up (Block Diagram of Configuration) 1.3 3.2 Limits and Measurement Result 1.4 2008 BANDWIDTH 1.5 4.1 Measurement Procedure 1.5 4.2 Test Set-Up (Block Diagram of Configuration) 1.5 4.1 Measurement Procedure 1.5 4.2 Test Set-Up (Block Diagram of Configuration) 1.5 4.3 Limits and Measurement Results 1.5 CONDUCTED SPURIOUS EMISSION 2.5 5.1 Measurement Procedure 2.5 2.5 Test Set-Up (Block Diagram of Configuration) 2.6 5.2 Test Set-Up (Block Diagram of Configuration) 2.6 6.8 ADIATED EMISSION 2.6 6.8 ADIATED EMISSION 3.6 6.1 Measurement Procedure 3.6 6.2 Test Set-Up (Block Diagram of Configuration) 3.6 6.1 Measurement Procedure 3.6 6.3 Limits and Measurement Result 3.7 Limit Sond Limits and Measurement Result 3.7 Limit Conducted Emission Test 4.7 4.7 Limit Conducted Emission Test 4.7 4.7 Final Procedure of Line Conducted Emission Test 4.7 4.7 Final Procedure of Line Conducted Emission Test 4.7 4.7 Final Procedure of Line Conducted Emission Test 4.7 4.7 Final Procedure of Line Conducted Emission Test 4.7 4.7 Final Procedure of Line Conducted Emission Test 4.7 4.7 Final Procedure of Line Conducted Emission Test 4.7 4.7 Final Procedure of Line Conducted Emission Test 4.7 4.7 Final Procedure of Line Conducted Emission Test 4.7 4.7 4.7 Final Procedure of Line Conducted Emission Test 4.7				
3.1. MEASUREMENT PROCEDURE. 16 3.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION) 11 3.3. LIMITS AND MEASUREMENT RESULT. 11 4. 20DB BANDWIDTH 11 4.1. MEASUREMENT PROCEDURE. 12 4.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION) 11 4.3. LIMITS AND MEASUREMENT RESULT. 13 5. CONDUCTED SPURIOUS EMISSION 26 5.1. MEASUREMENT PROCEDURE. 22 5.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION) 23 5.3. LIMITS AND MEASUREMENT RESULT 26 6. RADIATED EMISSION 36 6.1. MEASUREMENT PROCEDURE. 30 6.2. TEST SETUP. 30 6.2. TEST SETUP. 30 6.2. TEST SETUP. 30 6.3. LIMITS OF LINE CONDUCTED EMISSION TEST 44 7.1. LIMITS OF LINE CONDUCTED EMISSION TEST 44 7.2. BLOCK DIAGRAM OF LINE CONDUCTED EMISSION TEST 44 7.3. PRELIMINARY PROCEDURE OF LINE CONDUCTED EMISSION TEST 44 <t< td=""><td>_</td><td></td><td></td><td></td></t<>	_			
3.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION)	3.			
3.3. LIMITS AND MEASUREMENT RESULT. 4. 20DB BANDWIDTH. 1. 4.1. MEASUREMENT PROCEDURE. 4.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION). 1. 4.3. LIMITS AND MEASUREMENT RESULTS. 5. CONDUCTED SPURIOUS EMISSION. 2. 5.1. MEASUREMENT PROCEDURE. 5.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION). 2. 5.3. LIMITS AND MEASUREMENT RESULT. 2. 6. RADIATED EMISSION. 3. 6.1. MEASUREMENT PROCEDURE. 6.2. TEST SETUP. 6.3. LIMITS AND MEASUREMENT RESULT. 7. LIMIC CONDUCTED EMISSION TEST. 7. LIMIC SONDUCTED EMISSION TEST. 7.1. LIMITS OF LINE CONDUCTED EMISSION TEST. 7.2. BLOCK DIAGRAM OF LINE CONDUCTED EMISSION TEST. 7.3. PRELIMINARY PROCEDURE OF LINE CONDUCTED EMISSION TEST. 7.4. FINAL PROCEDURE OF LINE CONDUCTED EMISSION TEST. 7.5. TEST RESULT OF LINE CONDUCTED EMISSION TEST. 4. 7.4. FINAL PROCEDURE OF LINE CONDUCTED EMISSION TEST. 4. 7.5. TEST RESULT OF LINE CONDUCTED EMISSION TEST. 4. 7.5. TEST RESULT OF LINE CONDUCTED EMISSION TEST. 4. 8. NUMBER OF HOPPING FREQUENCY. 8. 1. MEASUREMENT PROCEDURE. 8. 1. MEASUREMENT PROCEDURE. 8. 2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION). 5. 9.3. LIMITS AND MEASUREMENT RESULT. 5. 10.1. MEASUREMENT PROCEDURE. 5. 10.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION). 5. 10.3. LIMITS AND MEASUREMENT RESULT. 5. 10.1. MEASUREMENT PROCEDURE. 5. 10.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION). 5. 10.3. LIMITS AND MEASUREMENT RESULT. 5. 10.1. MEASUREMENT PROCEDURE. 5. 10.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION). 5. 10.3. LIMITS AND MEASUREMENT RESULT. 5. 10.5. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION). 5. 10.3. LI				
4. 20DB BANDWIDTH 1 4.1. MEASUREMENT PROCEDURE 1* 4.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION) 1* 4.3. LIMITS AND MEASUREMENT RESULTS 1* 5. CONDUCTED SPURIOUS EMISSION 2* 5.1. MEASUREMENT PROCEDURE 2* 5.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION) 2* 5.3. LIMITS AND MEASUREMENT RESULT 2* 6. RADIATED EMISSION 3* 6.1. MEASUREMENT PROCEDURE 3* 6.2. TEST SETUP 3* 6.3. LIMITS AND MEASUREMENT RESULT 3* 7. LINE CONDUCTED EMISSION TEST 4* 7.1. LIMITS OF LINE CONDUCTED EMISSION TEST 4* 7.2. BLOCK DIAGRAM OF LINE CONDUCTED EMISSION TEST 4* 7.3. PRELIMINARY PROCEDURE OF LINE CONDUCTED EMISSION TEST 4* 7.4. FINAL PROCEDURE OF LINE CONDUCTED EMISSION TEST 4* 7.5. TEST RESULT OF LINE CONDUCTED EMISSION TEST 4* 8. NUMBER OF HOPPING FREQUENCY 5* 8.1. MEASUREMENT PROCEDURE 5* 8.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 5* 9.3. LIMITS AND MEASUREMENT RESULT 5* 9.9.1 MEASUREMENT PROCEDURE 5*			·	
4.1. MEASUREMENT PROCEDURE. 1 4.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION) 1 4.3. LIMITS AND MEASUREMENT RESULTS. 18 5. CONDUCTED SPURIOUS EMISSION 20 5.1. MEASUREMENT PROCEDURE. 22 5.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION) 24 5.3. LIMITS AND MEASUREMENT RESULT 26 6. RADIATED EMISSION 30 6.1. MEASUREMENT PROCEDURE. 33 6.2. TEST SETUP. 33 6.3. LIMITS AND MEASUREMENT RESULT 33 7. LINE CONDUCTED EMISSION TEST 44 7.1. LIMITS OF LINE CONDUCTED EMISSION TEST 44 7.2. BLOCK DIAGRAM OF LINE CONDUCTED EMISSION TEST 44 7.3. PRELIMINARY PROCEDURE OF LINE CONDUCTED EMISSION TEST 44 7.4. FINAL PROCEDURE OF LINE CONDUCTED EMISSION TEST 44 7.5. TEST RESULT OF LINE CONDUCTED EMISSION TEST 44 8. NUMBER OF HOPPING FREQUENCY 55 8.1. MEASUREMENT PROCEDURE. 55 8.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 56 8.3. LIMITS AND MEASUREMENT RESULT 55 9. TIME OF OCCUPANCY (DWELL TIME) 55 9.1. MEASUREMENT PROCEDURE. 55 <td>,</td> <td></td> <td></td> <td></td>	,			
4.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION) 1 4.3. LIMITS AND MEASUREMENT RESULTS. 13 5. CONDUCTED SPURIOUS EMISSION. 22 5.1. MEASUREMENT PROCEDURE. 26 5.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION) 22 5.3. LIMITS AND MEASUREMENT RESULT 26 6. RADIATED EMISSION 36 6.1. MEASUREMENT PROCEDURE. 36 6.2. TEST SETUP. 36 6.3. LIMITS AND MEASUREMENT RESULT 37 7. LINE CONDUCTED EMISSION TEST 44 7.1. LIMITS OF LINE CONDUCTED EMISSION TEST 44 7.2. BLOCK DIAGRAM OF LINE CONDUCTED EMISSION TEST 44 7.3. PRELIMINARY PROCEDURE OF LINE CONDUCTED EMISSION TEST 44 7.4. FINAL PROCEDURE OF LINE CONDUCTED EMISSION TEST 44 7.5. TEST RESULT OF LINE CONDUCTED EMISSION TEST 44 8. NUMBER OF HOPPING FREQUENCY 55 8.1. MEASUREMENT PROCEDURE 55 8.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 55 9.3. LIMITS AND MEASUREMENT RESULT 55 9.1. MEASUREMENT PROCEDURE. 55 9.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 55 9.3. LIMITS AND MEASUREMENT RESU	4.			
4.3. LIMITS AND MEASUREMENT RESULTS. 5. CONDUCTED SPURIOUS EMISSION. 2. 5.1. MEASUREMENT PROCEDURE. 5.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION) 2.3. LIMITS AND MEASUREMENT RESULT. 6. RADIATED EMISSION. 6.1. MEASUREMENT PROCEDURE. 6.2. TEST SET-UP. 6.3. LIMITS AND MEASUREMENT RESULT. 7. LINE CONDUCTED EMISSION TEST. 7.1. LIMITS OF LINE CONDUCTED EMISSION TEST. 7.2. BLOCK DIAGRAM OF LINE CONDUCTED EMISSION TEST. 7.3. PRELIMINARY PROCEDURE OF LINE CONDUCTED EMISSION TEST. 7.4. FINAL PROCEDURE OF LINE CONDUCTED EMISSION TEST. 7.5. TEST RESULT OF LINE CONDUCTED EMISSION TEST. 44. 7.5. TEST RESULT OF LINE CONDUCTED EMISSION TEST. 45. NUMBER OF HOPPING FREQUENCY 8. NUMBER OF HOPPING FREQUENCY 8. 1. MEASUREMENT PROCEDURE. 8. 2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION). 5. 8.3. LIMITS AND MEASUREMENT RESULT. 5. 9. 1. MEASUREMENT PROCEDURE. 5. 9. 1. MEASUREMENT PROCEDURE. 5. 1. MEASUREMENT PROCEDURE. 5. 1. MEASUREMENT PROCEDURE. 5. 2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION). 5. 3. LIMITS AND MEASUREMENT RESULT. 5. 1. MEASUREMENT PROCEDURE. 5. 1. MEASUREMENT PROCEDURE. 5. 2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION). 5. 3. LIMITS AND MEASUREMENT RESULT. 5. 1. MEASUREMENT PROCEDURE. 5. 1. MEASUREMENT PROCEDURE. 5. 2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION). 5. 3. LIMITS AND MEASUREMENT RESULT. 5. 1. MEASUREMENT PROCEDURE. 5. 1. MEASUREMENT PROCEDURE. 5. 2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION). 5. 5. 5. 5. 5. 5. 5. 5. 5. 5. 5. 5. 5. 5				
5. CONDUCTED SPURIOUS EMISSION 2. 5.1. MEASUREMENT PROCEDURE 2. 5.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION) 2. 5.3. LIMITS AND MEASUREMENT RESULT 2. 6. RADIATED EMISSION			· ·	
5.1. MEASUREMENT PROCEDURE. 22 5.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION) 26 5.3. LIMITS AND MEASUREMENT RESULT 22 6. RADIATED EMISSION 34 6.1. MEASUREMENT PROCEDURE. 36 6.2. TEST SETUP. 36 6.3. LIMITS AND MEASUREMENT RESULT. 37 7. LINE CONDUCTED EMISSION TEST. 47 7.1. LIMITS OF LINE CONDUCTED EMISSION TEST 44 7.2. BLOCK DIAGRAM OF LINE CONDUCTED EMISSION TEST 47 7.3. PRELIMINARY PROCEDURE OF LINE CONDUCTED EMISSION TEST 44 7.4. FINAL PROCEDURE OF LINE CONDUCTED EMISSION TEST 44 7.5. TEST RESULT OF LINE CONDUCTED EMISSION TEST 44 8. NUMBER OF HOPPING FREQUENCY 52 8.1. MEASUREMENT PROCEDURE 55 8.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 55 8.3. LIMITS AND MEASUREMENT RESULT 55 9.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 55 9.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 55 9.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 55 9.3. LIMITS AND MEASUREMENT RESULT 55 10. FREQUENCY SEPARATION 55 10.1. MEASUREMENT	5			
5.2. TEST SET-UP (BLOCK DIAGRAM OF CONFIGURATION) 22 5.3. LIMITS AND MEASUREMENT RESULT 26 6. RADIATED EMISSION 3 6.1. MEASUREMENT PROCEDURE 3 6.2. TEST SETUP 36 6.3. LIMITS AND MEASUREMENT RESULT 3 7. LINE CONDUCTED EMISSION TEST 4 7.1. LIMITS OF LINE CONDUCTED EMISSION TEST 4 7.2. BLOCK DIAGRAM OF LINE CONDUCTED EMISSION TEST 4 7.3. PRELIMINARY PROCEDURE OF LINE CONDUCTED EMISSION TEST 4 7.4. FINAL PROCEDURE OF LINE CONDUCTED EMISSION TEST 44 7.5. TEST RESULT OF LINE CONDUCTED EMISSION TEST 44 8. NUMBER OF HOPPING FREQUENCY 5 8.1. MEASUREMENT PROCEDURE 5 8.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 5 8.3. LIMITS AND MEASUREMENT RESULT 5 9.1 TIME OF OCCUPANCY (DWELL TIME) 5 9.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 5 9.3. LIMITS AND MEASUREMENT RESULT 5 10. FREQUENCY SEPARATION 5 10.1. MEASUREMENT PROCEDURE 5 10.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 5 10.3. LIMITS AND MEASUREMENT RESULT 5	٥.			
5.3. LIMITS AND MEASUREMENT RESULT 22 6. RADIATED EMISSION 34 6.1. MEASUREMENT PROCEDURE 3- 6.2. TEST SETUP 36 6.3. LIMITS AND MEASUREMENT RESULT 35 7. LINE CONDUCTED EMISSION TEST 44 7.1. LIMITS OF LINE CONDUCTED EMISSION TEST 44 7.2. BLOCK DIAGRAM OF LINE CONDUCTED EMISSION TEST 44 7.3. PRELIMINARY PROCEDURE OF LINE CONDUCTED EMISSION TEST 44 7.4. FINAL PROCEDURE OF LINE CONDUCTED EMISSION TEST 44 7.5. TEST RESULT OF LINE CONDUCTED EMISSION TEST 44 8. NUMBER OF HOPPING FREQUENCY 55 8.1. MEASUREMENT PROCEDURE 55 8.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 55 8.3. LIMITS AND MEASUREMENT RESULT 55 9.1. MEASUREMENT PROCEDURE 55 9.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 55 9.3. LIMITS AND MEASUREMENT RESULT 55 10. FREQUENCY SEPARATION 55 10.1. MEASUREMENT PROCEDURE 56 10.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 56 10.1. MEASUREMENT PROCEDURE 56 10.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION)				
6. RADIATED EMISSION 36 6.1. MEASUREMENT PROCEDURE 36 6.2. TEST SETUP 36 6.3. LIMITS AND MEASUREMENT RESULT 37 7. LINE CONDUCTED EMISSION TEST 44 7.1. LIMITS OF LINE CONDUCTED EMISSION TEST 44 7.2. BLOCK DIAGRAM OF LINE CONDUCTED EMISSION TEST 44 7.3. PRELIMINARY PROCEDURE OF LINE CONDUCTED EMISSION TEST 44 7.4. FINAL PROCEDURE OF LINE CONDUCTED EMISSION TEST 44 7.5. TEST RESULT OF LINE CONDUCTED EMISSION TEST 44 8. NUMBER OF HOPPING FREQUENCY 55 8.1. MEASUREMENT PROCEDURE 55 8.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 55 8.3. LIMITS AND MEASUREMENT RESULT 55 9.1. MEASUREMENT PROCEDURE 55 9.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 55 9.3. LIMITS AND MEASUREMENT RESULT 55 10. FREQUENCY SEPARATION 55 10.1. MEASUREMENT PROCEDURE 55 10.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 56 10.3. LIMITS AND MEASUREMENT RESULT 56 10.1. MEASUREMENT PROCEDURE 56 10.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) <td< td=""><td></td><td></td><td>· ·</td><td></td></td<>			· ·	
6.2. TEST SETUP. 33 6.3. LIMITS AND MEASUREMENT RESULT 33 7. LINE CONDUCTED EMISSION TEST 4 7.1. LIMITS OF LINE CONDUCTED EMISSION TEST 4 7.2. BLOCK DIAGRAM OF LINE CONDUCTED EMISSION TEST 4 7.3. PRELIMINARY PROCEDURE OF LINE CONDUCTED EMISSION TEST 44 7.4. FINAL PROCEDURE OF LINE CONDUCTED EMISSION TEST 44 7.5. TEST RESULT OF LINE CONDUCTED EMISSION TEST 44 8. NUMBER OF HOPPING FREQUENCY 5 8.1. MEASUREMENT PROCEDURE 5 8.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 5 8.3. LIMITS AND MEASUREMENT RESULT 5 9.1. MEASUREMENT PROCEDURE 5 9.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 5 9.3. LIMITS AND MEASUREMENT RESULT 5 10. FREQUENCY SEPARATION 5 10.1. MEASUREMENT PROCEDURE 5 10.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 5 10.1. MEASUREMENT PROCEDURE 5 10.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 5 10.3. LIMITS AND MEASUREMENT RESULT 5	6.			
6.3. LIMITS AND MEASUREMENT RESULT		6.1.	Measurement Procedure	34
7. LINE CONDUCTED EMISSION TEST		6.2.	TEST SETUP	36
7.1. LIMITS OF LINE CONDUCTED EMISSION TEST 4 7.2. BLOCK DIAGRAM OF LINE CONDUCTED EMISSION TEST 4 7.3. PRELIMINARY PROCEDURE OF LINE CONDUCTED EMISSION TEST 44 7.4. FINAL PROCEDURE OF LINE CONDUCTED EMISSION TEST 44 7.5. TEST RESULT OF LINE CONDUCTED EMISSION TEST 48 8. NUMBER OF HOPPING FREQUENCY 50 8.1. MEASUREMENT PROCEDURE 50 8.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 50 8.3. LIMITS AND MEASUREMENT RESULT 50 9.1. MEASUREMENT PROCEDURE 50 9.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 50 9.3. LIMITS AND MEASUREMENT RESULT 50 10.1 MEASUREMENT PROCEDURE 50 10.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 50 10.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 50 10.3. LIMITS AND MEASUREMENT RESULT 50		6.3.	LIMITS AND MEASUREMENT RESULT	37
7.2. BLOCK DIAGRAM OF LINE CONDUCTED EMISSION TEST 4 7.3. PRELIMINARY PROCEDURE OF LINE CONDUCTED EMISSION TEST 44 7.4. FINAL PROCEDURE OF LINE CONDUCTED EMISSION TEST 44 7.5. TEST RESULT OF LINE CONDUCTED EMISSION TEST 45 8. NUMBER OF HOPPING FREQUENCY 55 8.1. MEASUREMENT PROCEDURE. 55 8.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 55 8.3. LIMITS AND MEASUREMENT RESULT. 55 9. TIME OF OCCUPANCY (DWELL TIME) 55 9.1. MEASUREMENT PROCEDURE. 55 9.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 55 9.3. LIMITS AND MEASUREMENT RESULT. 55 10.1. MEASUREMENT PROCEDURE. 56 10.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 56 10.3. LIMITS AND MEASUREMENT RESULT. 56	7.	LINE	E CONDUCTED EMISSION TEST	47
7.3. PRELIMINARY PROCEDURE OF LINE CONDUCTED EMISSION TEST 44 7.4. FINAL PROCEDURE OF LINE CONDUCTED EMISSION TEST 44 7.5. TEST RESULT OF LINE CONDUCTED EMISSION TEST 45 8. NUMBER OF HOPPING FREQUENCY 55 8.1. MEASUREMENT PROCEDURE 55 8.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 55 8.3. LIMITS AND MEASUREMENT RESULT 55 9. TIME OF OCCUPANCY (DWELL TIME) 55 9.1. MEASUREMENT PROCEDURE 55 9.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 55 9.3. LIMITS AND MEASUREMENT RESULT 55 10. FREQUENCY SEPARATION 56 10.1. MEASUREMENT PROCEDURE 56 10.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 56 10.3. LIMITS AND MEASUREMENT RESULT 56 10.3. LIMITS AND MEASUREMENT RESULT 56		7.1.		
7.4. FINAL PROCEDURE OF LINE CONDUCTED EMISSION TEST .44 7.5. TEST RESULT OF LINE CONDUCTED EMISSION TEST .45 8. NUMBER OF HOPPING FREQUENCY .52 8.1. MEASUREMENT PROCEDURE .52 8.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) .52 8.3. LIMITS AND MEASUREMENT RESULT .52 9. TIME OF OCCUPANCY (DWELL TIME) .52 9.1. MEASUREMENT PROCEDURE .52 9.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) .52 9.3. LIMITS AND MEASUREMENT RESULT .52 10.1. MEASUREMENT PROCEDURE .52 10.1. MEASUREMENT PROCEDURE .56 10.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) .56 10.3. LIMITS AND MEASUREMENT RESULT .56		7.2.	BLOCK DIAGRAM OF LINE CONDUCTED EMISSION TEST	47
7.5. TEST RESULT OF LINE CONDUCTED EMISSION TEST 45 8. NUMBER OF HOPPING FREQUENCY 57 8.1. MEASUREMENT PROCEDURE 52 8.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 52 8.3. LIMITS AND MEASUREMENT RESULT 52 9. TIME OF OCCUPANCY (DWELL TIME) 52 9.1. MEASUREMENT PROCEDURE 52 9.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 53 9.3. LIMITS AND MEASUREMENT RESULT 53 10.1 MEASUREMENT PROCEDURE 56 10.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 56 10.3. LIMITS AND MEASUREMENT RESULT 56 10.3. LIMITS AND MEASUREMENT RESULT 56		7.3.		
8. NUMBER OF HOPPING FREQUENCY 53 8.1. Measurement Procedure 53 8.2. Test Setup (Block Diagram of Configuration) 53 8.3. Limits and Measurement Result 55 9. TIME OF OCCUPANCY (DWELL TIME) 55 9.1. Measurement Procedure 56 9.2. Test Setup (Block Diagram of Configuration) 55 9.3. Limits and Measurement Result 55 10. FREQUENCY SEPARATION 56 10.1. Measurement Procedure 56 10.2. Test Setup (Block Diagram of Configuration) 56 10.3. Limits and Measurement Result 56				
8.1. MEASUREMENT PROCEDURE 55 8.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 55 8.3. LIMITS AND MEASUREMENT RESULT 55 9. TIME OF OCCUPANCY (DWELL TIME) 55 9.1. MEASUREMENT PROCEDURE 55 9.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 55 9.3. LIMITS AND MEASUREMENT RESULT 55 10. FREQUENCY SEPARATION 56 10.1. MEASUREMENT PROCEDURE 56 10.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 56 10.3. LIMITS AND MEASUREMENT RESULT 56				
8.2. Test Setup (Block Diagram of Configuration). 55 8.3. Limits and Measurement Result. 55 9. TIME OF OCCUPANCY (DWELL TIME). 55 9.1. Measurement Procedure. 55 9.2. Test Setup (Block Diagram of Configuration). 55 9.3. Limits and Measurement Result. 55 10. FREQUENCY SEPARATION. 56 10.1. Measurement Procedure. 56 10.2. Test Setup (Block Diagram of Configuration). 56 10.3. Limits and Measurement Result. 56	8.		·	
8.3. LIMITS AND MEASUREMENT RESULT 55 9. TIME OF OCCUPANCY (DWELL TIME) 55 9.1. MEASUREMENT PROCEDURE 55 9.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 55 9.3. LIMITS AND MEASUREMENT RESULT 55 10. FREQUENCY SEPARATION 56 10.1. MEASUREMENT PROCEDURE 56 10.2. TEST SETUP (BLOCK DIAGRAM OF CONFIGURATION) 56 10.3. LIMITS AND MEASUREMENT RESULT 56				
9. TIME OF OCCUPANCY (DWELL TIME) 53 9.1. Measurement Procedure 52 9.2. Test Setup (Block Diagram of Configuration) 53 9.3. Limits and Measurement Result 55 10. FREQUENCY SEPARATION 56 10.1. Measurement Procedure 56 10.2. Test Setup (Block Diagram of Configuration) 56 10.3. Limits and Measurement Result 56			· ·	
9.1. MEASUREMENT PROCEDURE	_			
9.2. Test Setup (Block Diagram of Configuration). 52 9.3. Limits and Measurement Result. 52 10. FREQUENCY SEPARATION. 56 10.1. Measurement Procedure. 56 10.2. Test Setup (Block Diagram of Configuration). 56 10.3. Limits and Measurement Result. 56	9.		·	
9.3. LIMITS AND MEASUREMENT RESULT 52 10. FREQUENCY SEPARATION 50 10.1. MEASUREMENT PROCEDURE 50 10.2. Test Setup (Block Diagram of Configuration) 50 10.3. LIMITS AND MEASUREMENT RESULT 50				
10. FREQUENCY SEPARATION 56 10.1. Measurement Procedure 56 10.2. Test Setup (Block Diagram of Configuration) 56 10.3. Limits and Measurement Result 56			· ·	
10.1. Measurement Procedure				
10.2. Test Setup (Block Diagram of Configuration)	10		·	
10.3. LIMITS AND MEASUREMENT RESULT				
			·	
	11		LIMITS AND INFASUREMENT RESULT	56 57





1. SUMMARY

1.1. TEST STANDARDS

The tests were performed according to following standards:

FCC Rules Part 15.247: Frequency Hopping, Direct Spread Spectrum and Hybrid Systems that are in operation within the bands of 902-928 MHz, 2400-2483.5 MHz, and 5725-5850 MHz

ANSI C63.10:2013: American National Standard for Testing Unlicensed Wireless Devices

1.2. Test Description

FCC PART 15.247				
FCC Part 15.207	AC Power Conducted Emission	PASS		
FCC Part 15.247(a)(1)(i)	20dB Bandwidth	PASS		
FCC Part 15.247(d)	Spurious RF Conducted Emission	PASS		
FCC Part 15.247(b)	Maximum Peak Output Power	PASS		
FCC Part 15.247(b)	Pseudorandom Frequency Hopping Sequence	PASS		
FCC Part 15.247(a)(1)(iii)	Number of hopping frequency& Time of Occupancy	PASS		
FCC Part 15.247(a)(1)	Frequency Separation	PASS		
FCC Part 15.205/15.209	Radiated Emissions	PASS		
FCC Part 15.247(d)	Band Edge Compliance of RF Emission	PASS		



Page 5 of 58 Report No.: HK1901210164E

1.3. Test Facility

1.3.1 Address of the test laboratory

Shenzhen HUAK Testing Technology Co., Ltd.

Add.:1F, B2 Building, Junfeng Zhongcheng Zhizao Innovation Park, Heping Community, Fuhai Street, Bao'an District, Shenzhen, China

There is one 3m semi-anechoic chamber and two line conducted labs for final test. The Test Sites meet the requirements in documents ANSI C63.4 and CISPR 32/EN 55032 requirements.

1.3.2 Laboratory accreditation

The test facility is recognized, certified, or accredited by the following organizations:

IC Registration No.: 21210

The 3m alternate test site of Shenzhen HUAK Testing Technology Co., Ltd. EMC Laboratory has been registered by Certification and Engineer Bureau of Industry Canada for the performance of with Registration No.: 21210 on May 24, 2016.

FCC Registration No.: CN1229
Test Firm Registration Number: 616276

1.4. Statement of the measurement uncertainty

The data and results referenced in this document are true and accurate. The reader is cautioned that there may be errors within the calibration limits of the equipment and facilities. The measurement uncertainty was calculated for all measurements listed in this test report acc. to CISPR 16 - 4 "Specification for radio disturbance and immunity measuring apparatus and methods – Part 4: Uncertainty in EMC Measurements" and is documented in the Shenzhen HUAK Testing Technology Co., Ltd. quality system acc. to DIN EN ISO/IEC 17025. Furthermore, component and process variability of devices similar to that tested may result in additional deviation. The manufacturer has the sole responsibility of continued compliance of the device.

Hereafter the best measurement capability for HUAK laboratory is reported:

Test	Measurement Uncertainty	Notes
Transmitter power conducted	±0.57 dB	(1)
Transmitter power Radiated	±2.20 dB	(1)
Conducted spurious emission 9KHz-40 GHz	±2.20 dB	(1)
Occupied Bandwidth	±0.01ppm	(1)
Radiated Emission 30~1000MHz	±4.10dB	(1)
Radiated Emission Above 1GHz	±4.32dB	(1)
Conducted Disturbance0.15~30MHz	±3.20dB	(1)

⁽¹⁾ This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.





2. GENERAL INFORMATION

2.1. Environmental conditions

During the measurement the environmental conditions were within the listed ranges:

Normal Temperature:	25°C
Relative Humidity:	55 %
Air Pressure:	101 kPa

2.2. General Description of EUT

Product Name:	4K UST Laser Projector
Model/Type reference:	VA-LT002
Power supply:	100-240VAC
Version:	V4.2
Modulation:	GFSK, π/4DQPSK, 8DPSK
Operation frequency:	2402MHz~2480MHz
Channel number:	79
Channel separation:	1MHz
Antenna type:	PFC Antenna
Antenna gain:	3.45dBi
Hardware Version:	LT002-TV-PCB-VERB1 V02
Software Version:	VAVA_V1.00_20180905.183616

Note: For more details, refer to the user's manual of the EUT.

2.3. Description of Test Modes and Test Frequency

The Applicant provides communication tools software to control the EUT for staying in continuous transmitting and receiving mode for testing.

There are 79 channels provided to the EUT and Channel 00/39/78 was selected for testing.

Operation Frequency:

Channel	Frequency (MHz)	
00	2402	
01	2403	
i i	:	
38	2440	
39	2441	
40	2442	
÷	÷	
77	2479	
78	2480	

Note: The line display in grey were the channel selected for testing



Page 7 of 58 Report No.: HK1901210164E

NO.	TEST MODE DESCRIPTION	
1	Low channel TX	
2	Middle channel TX	
3	High channel TX	
4	Normal Operating (BT)	

Note:

1. Only the result of the worst case was recorded in the report, if no other cases.

Configure :		
	EUT	



2.4. Related Submittal(s) / Grant (s)

This submittal(s) (test report) is intended to comply with Section 15.247 of the FCC Part 15, Subpart C Rules.

Report No.: HK1901210164E

2.5. Modifications

No modifications were implemented to meet testing criteria.

2.6. Receiver Input Bandwidth

The input bandwidth of the receiver is 1.3MHZ,In every connection one Bluetooth device is the master and the other one is slave. The master determines the hopping sequence. The slave follows this sequence. Both devices shift between RX and TX time slot according to the clock of the master. Additionally the type of connection(e.g. single of multislot packet) is set up at the beginning of the connection. The master adapts its hopping frequency and its TX/RX timing according to the packet type of the connection. Also the slave of the connection will use these settings.

Repeating of a packet has no influence on the hopping sequence. The hopping sequence generated by the master of the connection will be followed in any case. That means, a repeated packet will not be send on the same frequency, it is send on the next frequency of the hopping sequence.

2.7. Example of a Hopping Sequence in Data Mode

Example of a 79 hopping sequence in data mode: 40,21,44,23,42,53,46,55,48,33,52,35,50,65,54,67 56,37,60,39,58,69,62,71,64,25,68,27,66,57,70,59 72,29,76,31,74,61,78,63,01,41,05,43,03,73,07,75 09,45,13,47,11,77,15,00,64,49,66,53,68,02,70,06 01, 51, 03, 55, 05, 04

2.8. Equally Average Use of Frequencies and Behaviour

The generation of the hopping sequence in connection mode depends essentially on two input values:

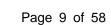
- 1. LAP/UAP of the master of the connection.
- 2. Internal master clock

The LAP(lower address part) are the 24 LSB's of the 48 BD_ADDRESS. The BD_ADDRESS is an unambiguous number of every Bluetooth unit. The UAP(upper address part) are the 24MSB's of the 48BD_ADDRESS

The internal clock of a Bluetooth unit is derived from a free running clock which is never adjusted and is never turned off. For ehavior zation with other units only offset are used. It has no relation to the time of the day. Its resolution is at least half the RX/TX slot length of 312.5us. The clock has a cycle of about one day(23h30). In most case it is implemented as 28 bit counter. For the deriving of the hopping sequence the entire. LAP(24 bits), 4LSB's (4bits) (Input 1) and the 27MSB's of the clock (Input 2) are used. With this input values different mathematical procedures (permutations, additions, XOR-operations) are performed to generate te Sequence. This will be done at the beginning of every new transmission.

Regarding short transmissions the Bluetooth system has the following 8 ehavior:

The first connection between the two devices is established, a hopping sequence was generated. For Transmitting the wanted data the complete hopping sequence was not used. The connection ended. The second connection will be established. A new hopping sequence is generated. Due to the fact the Bluetooth clock has a different value, because the period between the two transmission is longer(and it Cannot be shorter) than the minimum resolution of the clock(312.5us). The hopping sequence will always Differ from the first one.





2.9. Equipment Used

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	L.I.S.N. Artificial Mains Network	R&S	ENV216	HKE-002	Dec. 27, 2018	1 Year
2.	Receiver	R&S	ESCI 7	HKE-010	Dec. 27, 2018	1 Year
3.	RF automatic control unit	Tonscend	JS0806-2	HKE-060	Dec. 27, 2018	1 Year
4.	Spectrum analyzer	R&S	FSP40	HKE-025	Dec. 27, 2018	1 Year
5.	Spectrum analyzer	Agilent	N9020A	HKE-048	Dec. 27, 2018	1 Year
6.	Preamplifier	Schwarzbeck	BBV 9743	HKE-006	Dec. 27, 2018	1 Year
7.	EMI Test Receiver	Rohde & Schwarz	ESCI 7	HKE-010	Dec. 27, 2018	1 Year
8.	Bilog Broadband Antenna	Schwarzbeck	VULB9163	HKE-012	Dec. 27, 2018	1 Year
9.	Loop Antenna	Schwarzbeck	FMZB 1519 B	HKE-014	Dec. 27, 2018	1 Year
10.	Horn Antenna	Schewarzbeck	9120D	HKE-013	Dec. 27, 2018	1 Year
11.	Pre-amplifier	EMCI	EMC051845 SE	HKE-015	Dec. 27, 2018	1 Year
12.	Pre-amplifier	Agilent	83051A	HKE-016	Dec. 27, 2018	1 Year
13.	EMI Test Software EZ-EMC	Tonscend	JS1120-B Version	HKE-083	Dec. 27, 2018	N/A
14.	Power Sensor	Agilent	E9300A	HKE-086	Dec. 27, 2018	1 Year
15.	Spectrum analyzer	Agilent	N9020A	HKE-048	Dec. 27, 2018	1 Year
16.	Signal generator	Agilent	N5182A	HKE-029	Dec. 27, 2018	1 Year
17.	Signal Generator	Agilent	83630A	HKE-028	Dec. 27, 2018	1 Year
18.	Shielded room	Shiel Hong	4*3*3	HKE-039	Dec. 27, 2018	3 Year

The calibration interval was one year



3. Peak Output Power

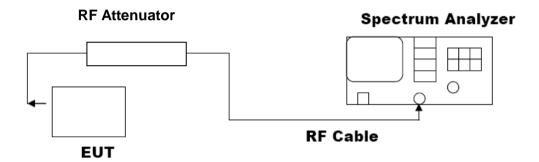
3.1. Measurement Procedure

For peak power test:

- 1. Connect EUT RF output port to the Spectrum Analyzer through an RF attenuator
- 2. Span: Approximately five times the 20 dB bandwidth, centered on a hopping channel.
- 3. RBW > 20 dB bandwidth of the emission being measured.
- 4. VBW ≥RBW.
- 5. Sweep: Auto.
- 6. Detector function: Peak.
- 7. Trace: Max hold.

Allow trace to stabilize. Use the marker-to-peak function to set the marker to the peak of the emission. The indicated level is the peak output power, after any corrections for external attenuators and cables.

3.2. Test Set-Up (Block Diagram of Configuration)



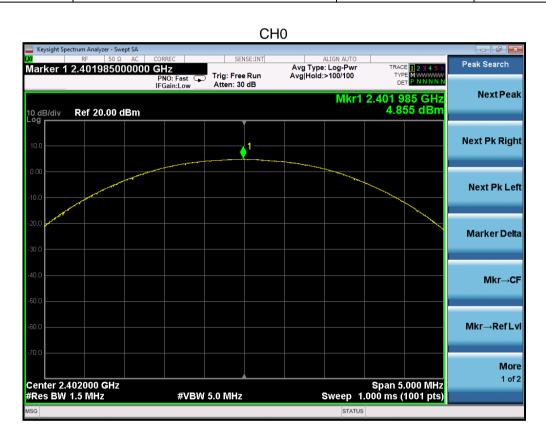




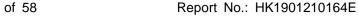
3.3. Limits and Measurement Result

PEAK OUTPUT POWER MEASUREMENT RESULT FOR GFSK MOUDULATION				
Frequency (GHz) Peak Power (dBm) Applicable Limits (dBm) Pass or Fail				
2.402	4.855	30	Pass	
2.441	5.142	30	Pass	
2.480	5.461	30	Pass	

Report No.: HK1901210164E















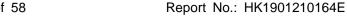
Page 13 of 58 Report No.: HK1901210164E

PEAK OUTPUT POWER MEASUREMENT RESULT FOR II /4-DQPSK MODULATION				
Frequency (GHz) Peak Power (dBm) Applicable Limits (dBm) Pass or Fail				
2.402	4.867	30	Pass	
2.441	5.154	30	Pass	
2.480	5.450	30	Pass	











CH78





Report No.: HK1901210164E Page 15 of 58

PEAK OUTPUT POWER MEASUREMENT RESULT FOR 8-DPSK MOUDULATION			
Frequency (GHz)	Peak Power (dBm)	Applicable Limits (dBm)	Pass or Fail
2.402	4.869	30	Pass
2.441	5.148	30	Pass
2.480	5.441	30	Pass











CH78



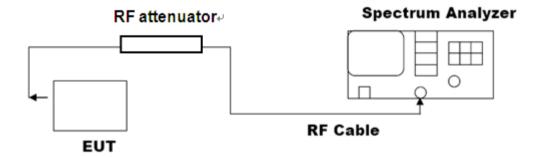


4. 20dB Bandwidth

4.1. Measurement Procedure

- 1. Connect EUT RF output port to the Spectrum Analyzer through an RF attenuator
- 2, Set the EUT Work on the top, the middle and the bottom operation frequency individually.
- 3. Set Span = approximately 2 to 5 times the 20 dB bandwidth, centered on a hoping channel
 The nominal IF filter bandwidth (3 dB RBW) shall be in the range of 1% to 5% of the OBW and video
 bandwidth (VBW) shall be approximately three times RBW; Sweep = auto; Detector function = peak
- 4. Set SPA Trace 1 Max hold, then View.

4.2. Test Set-Up (Block Diagram of Configuration)





4.3. Limits and Measurement Results

MEASUREMENT RESULT FOR GFSK MOUDULATION				
Anni Paral In I Provide	Measurement Result			
Applicable Limits	Test Data (MHz)		Criteria	
	Low Channel	1.110	PASS	
N/A	Middle Channel	1.109	PASS	
	High Channel	1.109	PASS	

Report No.: HK1901210164E

TEST PLOT OF BANDWIDTH FOR LOW CHANNEL





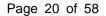
TEST PLOT OF BANDWIDTH FOR MIDDLE CHANNEL

Report No.: HK1901210164E



TEST PLOT OF BANDWIDTH FOR HIGH CHANNEL







 MEASUREMENT RESULT FOR [] /4-DQPSK MODULATION

 Measurement Result

 Test Data (MHz)
 Criteria

 Low Channel
 1.164
 PASS

 Middle Channel
 1.167
 PASS

 High Channel
 1.167
 PASS

Report No.: HK1901210164E

TEST PLOT OF BANDWIDTH FOR LOW CHANNEL





TEST PLOT OF BANDWIDTH FOR MIDDLE CHANNEL

Report No.: HK1901210164E



TEST PLOT OF BANDWIDTH FOR HIGH CHANNEL







 MEASUREMENT RESULT FOR 8-DPSK MOUDULATION

 Measurement Result

 Test Data (MHz)
 Criteria

 Low Channel
 1.108
 PASS

 Middle Channel
 1.109
 PASS

 High Channel
 1.109
 PASS

Report No.: HK1901210164E

TEST PLOT OF BANDWIDTH FOR LOW CHANNEL





TEST PLOT OF BANDWIDTH FOR MIDDLE CHANNEL

Report No.: HK1901210164E



TEST PLOT OF BANDWIDTH FOR HIGH CHANNEL





5. Conducted Spurious Emission

5.1. Measurement Procedure

- 1. Connect EUT RF output port to the Spectrum Analyzer through an RF attenuator
- 2. Set the EUT Work on the top, the Middle and the bottom operation frequency individually.
- 3. Set the Span = wide enough to capture the peak level of the in-band emission and all spurious emissions from the lowest frequency generated in the EUT up through the 10th harmonic. RBW = 100 kHz; VBW= 300 kHz; Sweep = auto; Detector function = peak.
- 4. Set SPA Trace 1 Max hold, then View.

5.2. Test Set-Up (Block Diagram of Configuration)

The same as described in section 4.2

5.3. Limits and Measurement Result

LIMITS AND MEASUREMENT RESULT			
Analia da Limita	Measurement Result		
Applicable Limits	Test Data	Criteria	
In any 100 KHz Bandwidth Outside the	At least -20dBc than the limit		
frequency band in which the spread spectrum	Specified on the BOTTOM	PASS	
intentional radiator is operating, the radio	Channel		
frequency power that is produce by the intentional			
radiator shall be at least 20 dB below that in			
100KHz bandwidth within the band that contains			
the highest level of the desired power.	At least -20dBc than the limit	DACC	
In addition, radiation emissions which fall in the	Specified on the TOP Channel	PASS	
restricted bands, as defined in §15.205(a), must			
also comply with the radiated emission limits			
specified in§15.209(a))			



TEST RESULT FOR ENTIRE FREQUENCY RANGE

Report No.: HK1901210164E

TEST PLOT OF OUT OF BAND EMISSIONS WITH THE WORST CASE OF GFSK MODULATION IN LOW CHANNEL



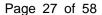


TEST PLOT OF OUT OF BAND EMISSIONS OF GFSK MODULATION IN MIDDLE CHANNEL

Report No.: HK1901210164E



STATUS



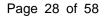


TEST PLOT OF OUT OF BAND EMISSIONS OF GFSK MODULATION IN HIGH CHANNEL

Report No.: HK1901210164E



Note: The peak emissions without marker on the above plots are fundamental wave and need not to compare with the limit. The GFSK modulation is the worst case and only those data recorded in the report.



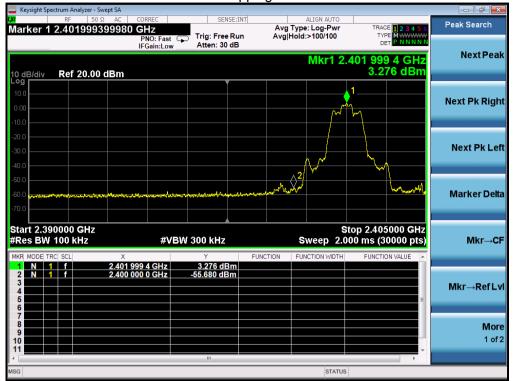


TEST RESULT FOR BAND EDGE

Report No.: HK1901210164E

GFSK MODULATION IN LOW CHANNEL

Hopping off





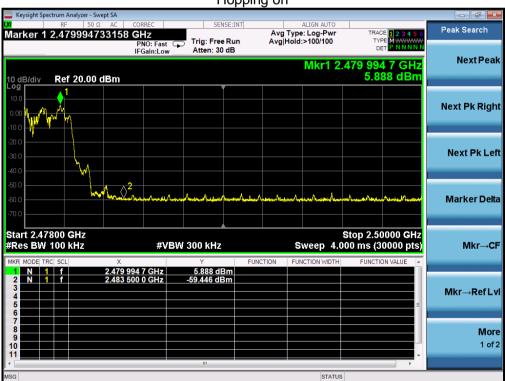


GFSK MODULATION IN HIGH CHANNEL

Report No.: HK1901210164E

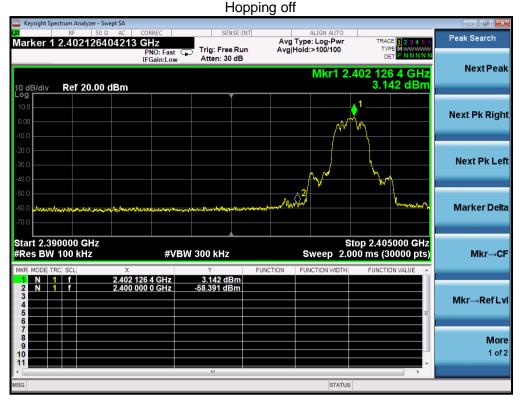
Hopping off







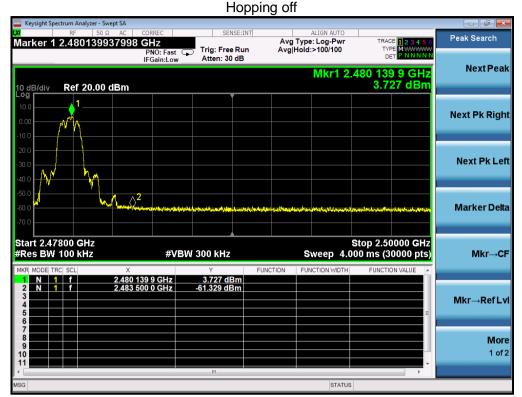
π /4-DQPSK MODULATION IN LOW CHANNEL







π /4-DQPSK MODULATION IN HIGH CHANNEL







8-DPSK MODULATION IN LOW CHANNEL

Report No.: HK1901210164E

Hopping off







8-DPSK MODULATION IN HIGH CHANNEL

Report No.: HK1901210164E

Hopping off







6. Radiated Emission

6.1. Measurement Procedure

 The EUT was placed on the top of the turntable 0.8 or 1.5 meter above ground. The phase center of the receiving antenna mounted on the top of a height-variable antenna tower was placed 3 meters far away from the turntable.

Report No.: HK1901210164E

- 2. Power on the EUT and all the supporting units. The turntable was rotated by 360 degrees to determine the position of the highest radiation.
- 3. The height of the broadband receiving antenna was varied between one meter and four meters above ground to find the maximum emissions field strength of both horizontal and vertical polarization.
- 4. For each suspected emissions, the antenna tower was scan (from 1 M to 4 M) and then the turntable was rotated (from 0 degree to 360 degrees) to find the maximum reading.
- 5. Set the test-receiver system to Peak or CISPR quasi-peak Detect Function with specified bandwidth under Maximum Hold Mode.
- 6. For emissions above 1GHz, use 1MHz RBW and 3MHz VBW for peak reading. Place the measurement antenna away from each area of the EUT determined to be a source of emissions at the specified measurement distance, while keeping the measurement antenna aimed at the source of emissions at each frequency of significant emissions, with polarization oriented for maximum response. The measurement antenna may have to be higher or lower than the EUT, depending on the radiation pattern of the emission and staying aimed at the emission source for receiving the maximum signal. The final measurement antenna elevation shall be that which maximizes the emissions. The measurement antenna elevation for maximum emissions shall be restricted to a range of heights of from 1 m to 4 m above the ground or reference ground plane.
- 7. When the radiated emissions limits are expressed in terms of the average value of the emissions, and pulsed operation is employed, the measurement field strength shall be determined by averaging over one complete pulse train, including blanking intervals, as long as the pulse train does not exceed 0.1 seconds. As an alternative (provided the transmitter operates for longer than 0.1 seconds) or in cases where the pulse train exceeds 0.1 seconds, the measured field strength shall be determined from the average absolute voltage during a 0.1 second interval during which the field strength is at its maximum values.
- 8.If the emissions level of the EUT in peak mode was 3 dB lower than the average limit specified, then testing will be stopped and peak values of EUT will be reported, otherwise, the emissions which do not have 3 dB margin will be repeated one by one using the quasi-peak method for below 1GHz.
- 9. For testing above 1GHz, the emissions level of the EUT in peak mode was lower than average limit (that means the emissions level in peak mode also complies with the limit in average mode), then testing will be stopped and peak values of EUT will be reported, otherwise, the emissions will be measured in average mode again and reported.
- 10. In case the emission is lower than 30MHz, loop antenna has to be used for measurement and the recorded data should be QP measured by receiver. High Low scan is not required in this case.

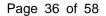


Page 35 of 58 Report No.: HK1901210164E

The following table is the setting of spectrum analyzer and receiver.

Spectrum Parameter	Setting
Start ~Stop Frequency	9KHz~150KHz/RB 200Hz for QP
Start ~Stop Frequency	150KHz~30MHz/RB 9KHz for QP
Start ~Stop Frequency	30MHz~1000MHz/RB 120KHz for QP
Start ~Stop Frequency	1GHz~26.5GHz 1MHz/3MHz for Peak, 1MHz/10Hz for Average

Receiver Parameter	Setting
Start ~Stop Frequency	9KHz~150KHz/RB 200Hz for QP
Start ~Stop Frequency	150KHz~30MHz/RB 9KHz for QP
Start ~Stop Frequency	30MHz~1000MHz/RB 120KHz for QP

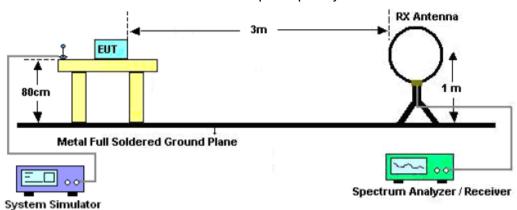




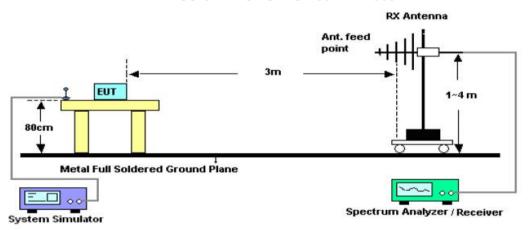
6.2. Test Setup

Radiated Emission Test-Setup Frequency Below 30MHz

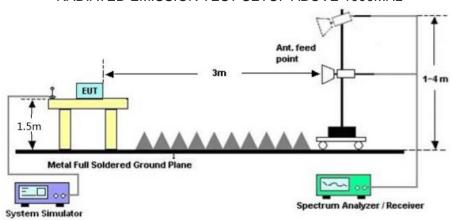
Report No.: HK1901210164E

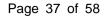


RADIATED EMISSION TEST SETUP 30MHz-1000MHz



RADIATED EMISSION TEST SETUP ABOVE 1000MHz





Report No.: HK1901210164E



6.3. Limits and Measurement Result

15.209&RSS-GEN Limit in the below table has to be followed

Frequencies (MHz)	Field Strength (micorvolts/meter)	Measurement Distance (meters)
0.009~0.490	2400/F(KHz)	300
0.490~1.705	24000/F(KHz)	30
1.705~30.0	30	30
30~88	100	3
88~216	150	3
216~960	200	3
Above 960	500	3

Note: All modes were tested For restricted band radiated emission,

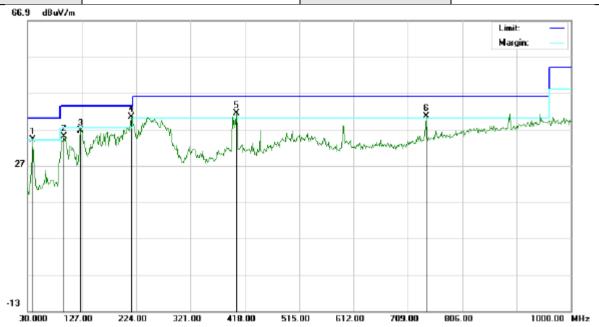
the test records reported below are the worst result compared to other modes.

Page 38 of 58 Report No.: HK1901210164E

RADIATED EMISSION BELOW 30MHZ

No emission found between lowest internal used/generated frequencies to 30MHz. **RADIATED EMISSION BELOW 1GHZ**

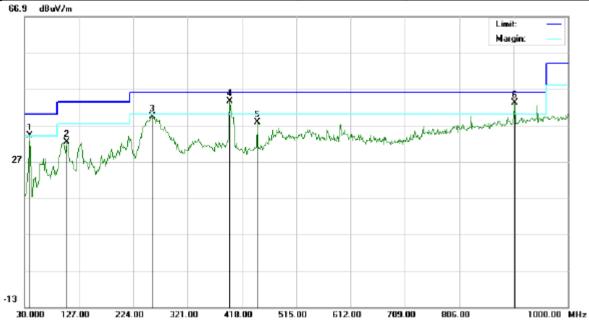
EUT	4K UST Laser Projector	Model Name	VA-LT002
Temperature	25°C	Relative Humidity	55.4%
Pressure	960hPa	Test Voltage	Normal Voltage
Test Mode	Mode 4	Antenna	Horizontal



No.	Mk	Freq.	Reading	Factor	Measurement	Limit	Over	Detector	Antenna Height	Table Degree	Comment
	•	MHz	dBuV	dBuV/m	dBuV/m	dBuV/m	dB		cm	degree	
1	į	39.7000	13.58	20.61	34.19	40.00	-5.81	peak			
2		94.6667	18.56	16.48	35.04	43.50	-8.46	peak			
3		125.3833	17.10	19.47	36.57	43.50	-6.93	peak			
4	*	215.9167	21.96	18.50	40.46	43.50	-3.04	peak			
5	į	403.4500	15.83	25.49	41.32	46.00	-4.68	peak			
6	Ţ	741.3333	8.09	32.52	40.61	46.00	-5.39	peak			

Page 39 of 58 Report No.: HK1901210164E

EUT	4K UST Laser Projector	Model Name	VA-LT002
Temperature	25°C	Relative Humidity	55.4%
Pressure	960hPa	Test Voltage	Normal Voltage
Test Mode	Mode 4	Antenna	Vertical



No.	Mk	Freq.	Reading	Factor	Measurement	Limit	Over	Detector	Antenna Height		Comment
	•	MHz	dBuV	dBuV/m	dBuV/m	dBuV/m	dB		cm	degree	
1	į	39.7000	13.64	20.61	34.25	40.00	-5.75	peak			
2		105.9832	14.71	17.69	32.40	43.50	-11.10	peak			
3		257.9500	19.15	20.20	39.35	46.00	-6.65	peak			
4	*	396.9833	18.26	25.31	43.57	46.00	-2.43	peak			
5		445.4833	11.36	26.36	37.72	46.00	-8.28	peak			
6	į	904.6166	7.13	35.98	43.11	46.00	-2.89	peak			

RESULT: PASS

Note: 1. Factor=Antenna Factor + Cable loss, Margin=Measurement-Limit.

2. All test modes had been pre-tested. The mode 4 is the worst case and recorded in the report.



Page 40 of 58 Report No.: HK1901210164E

RADIATED EMISSION ABOVE 1GHZ

EUT	4K UST Laser Projector	Model Name	VA-LT002
Temperature	25°C	Relative Humidity	55.4%
Pressure	960hPa	Test Voltage	Normal Voltage
Test Mode	Mode 1	Antenna	Horizontal

Frequency	Meter Reading	Factor	Emission Level	Limits	Margin	Value Type						
(MHz)	(dBµV)	(dB)	(dBµV/m)	(dBµV/m)	(dB)	value Type						
4804.011	45.78	7.12	52.9	74	-21.1	peak						
4804.011	40.45	7.12	47.57	54	-6.43	AVG						
7206.022	43.28	9.84	53.12	74	-20.88	peak						
7206.022	37.47	9.84	47.31	54	-6.69	AVG						
Remark:	Remark:											
Factor = Anter	nna Factor + Cabl	e Loss – Pre-a	amplifier.		Factor = Antenna Factor + Cable Loss – Pre-amplifier.							

EUT	4K UST Laser Projector	Model Name	VA-LT002
Temperature	25°C	Relative Humidity	55.4%
Pressure	960hPa	Test Voltage	Normal Voltage
Test Mode	Mode 1	Antenna	Vertical

Frequency	Meter Reading	Factor	Emission Level	Limits	Margin	Value Type
(MHz)	(dBµV)	(dB)	(dBµV/m)	(dBµV/m)	(dB)	value Type
4804.011	44.24	7.12	51.36	74	-22.64	peak
4804.011	39.54	7.12	46.66	54	-7.34	AVG
7206.022	42.18	9.84	52.02	74	-21.98	peak
7206.022	38.77	9.84	48.61	54	-5.39	AVG
emark:						



Page 41 of 58 Report No.: HK1901210164E

EUT	4K UST Laser Projector	Model Name	VA-LT002
Temperature	25°C	Relative Humidity	55.4%
Pressure	960hPa	Test Voltage	Normal Voltage
Test Mode	Mode 2	Antenna	Horizontal

Meter Reading	Factor	Emission Level	Limits	Margin	Value Type
(dBµV)	(dB)	(dBµV/m)	(dBµV/m)	(dB)	value Type
46.77	7.12	53.89	74	-20.11	peak
42.45	7.12	49.57	54	-4.43	AVG
43.85	9.84	53.69	74	-20.31	peak
38.27	9.84	48.11	54	-5.89	AVG
	(dBµV) 46.77 42.45 43.85	(dBµV) (dB) 46.77 7.12 42.45 7.12 43.85 9.84	(dBμV) (dB) (dBμV/m) 46.77 7.12 53.89 42.45 7.12 49.57 43.85 9.84 53.69	(dBμV) (dB) (dBμV/m) (dBμV/m) 46.77 7.12 53.89 74 42.45 7.12 49.57 54 43.85 9.84 53.69 74	(dBμV) (dB) (dBμV/m) (dBμV/m) (dBμV/m) 46.77 7.12 53.89 74 -20.11 42.45 7.12 49.57 54 -4.43 43.85 9.84 53.69 74 -20.31

EUT	4K UST Laser Projector	Model Name	VA-LT002
Temperature	25°C	Relative Humidity	55.4%
Pressure	960hPa	Test Voltage	Normal Voltage
Test Mode	Mode 2	Antenna	Vertical

Frequency	Meter Reading	Factor	Emission Level	Limits	Margin	Value Type
(MHz)	(dBµV)	(dB)	(dBµV/m)	(dBµV/m)	(dB)	value Type
4882.005	45.78	7.12	52.9	74	-21.1	peak
4882.005	41.52	7.12	48.64	54	-5.36	AVG
7323.140	44.12	9.84	53.96	74	-20.04	peak
7323.140	40.25	9.84	50.09	54	-3.91	AVG
emark:						

Page 42 of 58 Report No.: HK1901210164E

EUT	4K UST Laser Projector	Model Name	VA-LT002
Temperature	25°C	Relative Humidity	55.4%
Pressure	960hPa	Test Voltage	Normal Voltage
Test Mode	Mode 3	Antenna	Horizontal

Frequency	Meter Reading	Factor	Emission Level	Limits	Margin	Value Type
(MHz)	(dBµV)	(dB)	(dBµV/m)	(dBµV/m)	(dB)	value Type
4960.012	46.68	7.12	53.8	74	-20.2	peak
4960.012	42.14	7.12	49.26	54	-4.74	AVG
7440.027	43.52	9.84	53.36	74	-20.64	peak
7440.027	38.44	9.84	48.28	54	-5.72	AVG
Remark:	1		1			
Factor = Anter	na Factor + Cabl	e Loss – Pre-	amplifier.			

EUT	4K UST Laser Projector	Model Name	VA-LT002
Temperature	25°C	Relative Humidity	55.4%
Pressure	960hPa	Test Voltage	Normal Voltage
Test Mode	Mode 3	Antenna	Vertical

Frequency	Meter Reading	Factor	Emission Level	Limits	Margin	Value Type
(MHz)	(dBµV)	(dB)	(dBµV/m)	(dBµV/m)	(dB)	value Type
4960.012	45.18	7.12	52.3	74	-21.7	peak
4960.012	41.42	7.12	48.54	54	-5.46	AVG
7440.027	43.28	9.84	53.12	74	-20.88	peak
7440.027	39.19	9.84	49.03	54	-4.97	AVG
Remark:						
Factor = Anter	na Factor + Cable	e Loss – Pre-	amplifier.			

RESULT: PASS

Note:

Other emissions from 1G to 25 GHz are considered as ambient noise. No recording in the test report.

Factor = Antenna Factor + Cable loss - Amplifier gain, Over=Measure-Limit.

The "Factor" value can be calculated automatically by software of measurement system.

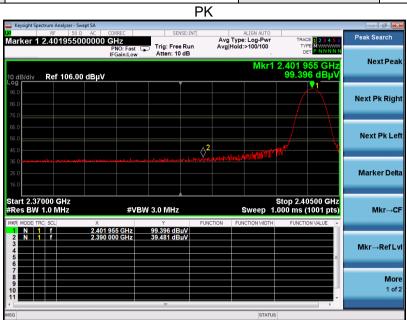
All test modes had been tested. The GFSK modulation is the worst case and recorded in the report.

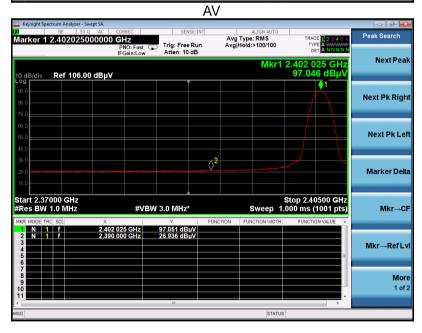


Page 43 of 58 Report No.: HK1901210164E

TEST RESULT FOR RESTRICTED BANDS REQUIREMENTS

EUT	4K UST Laser Projector	Model Name	VA-LT002
Temperature	25°C	Relative Humidity	55.4%
Pressure	960hPa	Test Voltage	Normal Voltage
Test Mode	Mode 1	Antenna	Horizontal





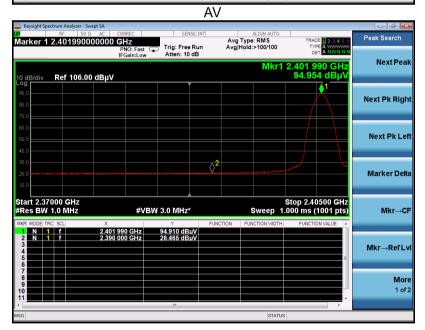


Page 44 of 58 Report No.: HK1901210164E

WATA V

EUT	4K UST Laser Projector	Model Name	VA-LT002
Temperature	25°C	Relative Humidity	55.4%
Pressure	960hPa	Test Voltage	Normal Voltage
Test Mode	Mode 1	Antenna	Vertical

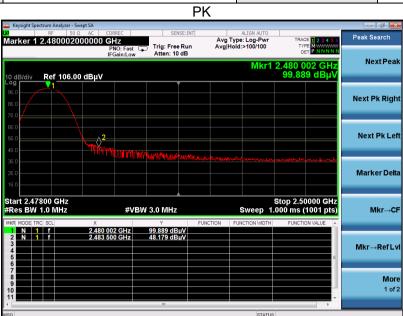


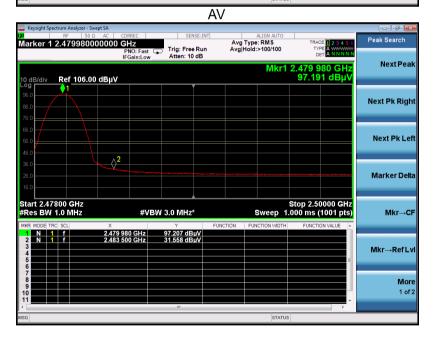




Page 45 of 58 Report No.: HK1901210164E

EUT	4K UST Laser Projector	Model Name	VA-LT002
Temperature	25°C	Relative Humidity	55.4%
Pressure	960hPa	Test Voltage	Normal Voltage
Test Mode	Mode 3	Antenna	Horizontal







Page 46 of 58 Report No.: HK1901210164E

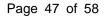
EUT	4K UST Laser Projector	Model Name	VA-LT002
Temperature	25°C	Relative Humidity	55.4%
Pressure	960hPa	Test Voltage	Normal Voltage
Test Mode	Mode 3	Antenna	Vertical





RESULT: PASS

Note: The factor had been edited in the "Input Correction" of the Spectrum Analyzer. So the Amplitude of test plots is equal to Reading level plus the Factor in dB. Use the A dB(μ V) to represent the Amplitude. Use the F dB(μ V/m) to represent the Field Strength. So A=F. All test modes had been pre-tested. The GFSK modulation is the worst case and recorded in the report.





7. LINE CONDUCTED EMISSION TEST

7.1. LIMITS OF LINE CONDUCTED EMISSION TEST

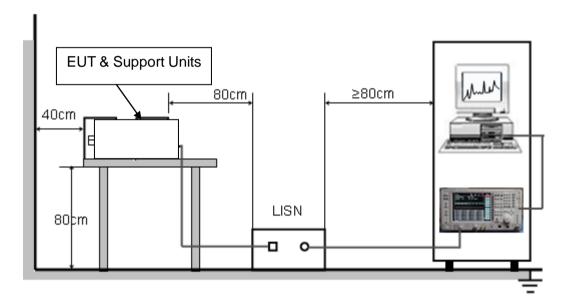
F	Maximum RF Line Voltage			
Frequency	Q.P.(dBuV)	Average(dBuV)		
150kHz~500kHz	66-56	56-46		
500kHz~5MHz	56	46		
5MHz~30MHz	60	50		

Report No.: HK1901210164E

Note:

- 1. The lower limit shall apply at the transition frequency.
- 2. The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 0.50 MHz.

7.2. BLOCK DIAGRAM OF LINE CONDUCTED EMISSION TEST



Page 48 of 58 Report No.: HK1901210164E

7.3. PRELIMINARY PROCEDURE OF LINE CONDUCTED EMISSION TEST

- 1. The equipment was set up as per the test configuration to simulate typical actual usage per the user's manual. When the EUT is a tabletop system, a wooden table with a height of 0.8 meters is used and is placed on the ground plane as per ANSI C63.10 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
- 2. Support equipment, if needed, was placed as per ANSI C63.10.
- 3. All I/O cables were positioned to simulate typical actual usage as per ANSI C63.10.
- 4. All support equipments received AC120V/60Hz power from a LISN, if any.
- 5. The EUT received DC 5V power from adapter which received AC120V/60Hz power from a LISN.
- 6. The test program was started. Emissions were measured on each current carrying line of the EUT using a spectrum Analyzer / Receiver connected to the LISN powering the EUT. The LISN has two monitoring points: Line 1 (Hot Side) and Line 2 (Neutral Side). Two scans were taken: one with Line 1 connected to Analyzer / Receiver and Line 2 connected to a 50 ohm load; the second scan had Line 1 connected to a 50 ohm load and Line 2 connected to the Analyzer / Receiver.
- 7. Analyzer / Receiver scanned from 150 kHz to 30MHz for emissions in each of the test modes.
- 8. During the above scans, the emissions were maximized by cable manipulation.
- 9. The test mode(s) were scanned during the preliminary test.

Then, the EUT configuration and cable configuration of the above highest emission level were recorded for reference of final testing.

7.4. FINAL PROCEDURE OF LINE CONDUCTED EMISSION TEST

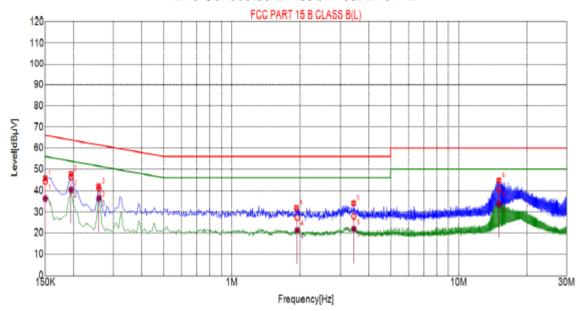
- 1. EUT and support equipment was set up on the test bench as per step 2 of the preliminary test.
- 2. A scan was taken on both power lines, Line 1 and Line 2, recording at least the six highest emissions. Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit. If EUT emission level was less –2dB to the A.V. limit in Peak mode, then the emission signal was re-checked using Q.P and Average detector.
- 3. The test data of the worst case condition(s) was reported on the Summary Data page.



Report No.: HK1901210164E

7.5. TEST RESULT OF LINE CONDUCTED EMISSION TEST

Line Conducted Emission Test Line 1-L

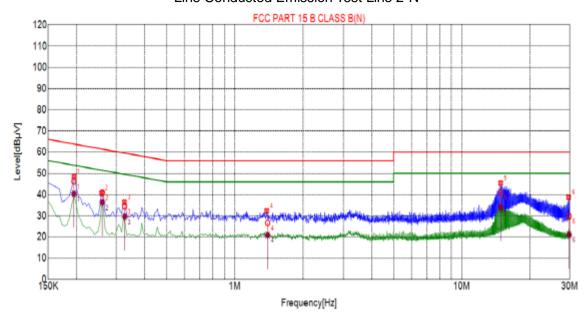


Susp	Suspected List							
NO.	Freq. [MHz]	Level [dBµV]	Factor [dB]	Limit [dBµV]	Margin [dB]	Detector		
1	0.1500	45.80	10.03	66.00	20.20	PK		
2	0.1950	47.88	10.03	63.82	15.94	PK		
3	0.2580	42.11	10.04	61.50	19.39	PK		
4	1.9275	31.96	10.14	56.00	24.04	PK		
5	3.4350	34.07	10.24	56.00	21.93	PK		
6	15.0495	44.69	9.96	60.00	15.31	PK		

Final Data List								
NO.	Freq. [MHz]	Factor [dB]	QP Value [dBµV]	QP Limit [dBµV]	QP Margin [d8]	AV Value [dBµV]	AV Limit [dBµV]	AV Mergin [dB]
1	0.1500	10.03	44.26	66.00	21.74	36.28	56.00	19.72
2	0.1950	10.03	46.30	63.82	17.52	40.36	53.82	13.46
3	0.2591	10.03	40.92	61.46	20.54	36.40	51.46	15.06
4	1.9454	10.14	27.28	56.00	28.72	21.24	46.00	24.76
5	3.4427	10.25	27.89	56.00	28.11	21.95	46.00	24.05
6	15.0539	9.96	40.62	60.00	19.38	33.80	50.00	16.20

Page 50 of 58 Report No.: HK1901210164E

Line Conducted Emission Test Line 2-N



Suspected List							
NO.	Freq. [MHz]	Level [dBµV]	Factor [dB]	Limit [dBµV]	Margin [dB]	Detector	
1	0.1950	48.51	10.03	63.82	15.31	PK	
2	0.2580	40.64	10.04	61.50	20.86	PK	
3	0.3255	36.33	10.05	59.57	23.24	PK	
4	1.3830	32.27	10.11	56.00	23.73	PK	
5	14.8560	45.36	9.95	60.00	14.64	PK	
6	29.6475	38.70	10.26	60.00	21.30	PK	

Final Data List								
NO.	Freq. [MHz]	Factor [dB]	QP Value [dBµV]	QP Limit [dBµV]	QP Margin [d8]	AV Value [dBµV]	AV Limit [dBµV]	AV Mergin [dB]
1	0.1947	10.03	46.29	63.83	17.54	40.36	53.83	13.47
2	0.2601	10.03	40.91	61.43	20.52	36.34	51.43	15.09
3	0.3263	10.05	34.43	59.54	25.11	29.65	49.54	19.89
4	1.3960	10.11	26.71	56.00	29.29	20.90	46.00	25.10
5	14.8594	9.95	41.14	60.00	18.86	33.94	50.00	16.06
6	29.8088	10.26	29.81	60.00	30.19	21.08	50.00	28.92

RESULT: PASS

Note: All the test modes had been tested, the mode 1 was the worst case. Only the data of the worst case would be record in this test report.





8. Number of Hopping Frequency

8.1. Measurement Procedure

The EUT shall have its hopping function enabled. Use the following spectrum analyzer settings:

1. Span: The frequency band of operation. Depending on the number of channels the device supports, it may be necessary to divide the frequency range of operation across multiple spans, to allow the individual channels to be clearly seen.

Report No.: HK1901210164E

- 2. RBW: To identify clearly the individual channels, set the RBW to less than 30% of the channel spacing or the 20 dB bandwidth, whichever is smaller.
- 3. VBW > RBW. Sweep: Auto. Detector function: Peak. Trace: Max hold.
- 4. Allow the trace to stabilize.

8.2. Test Setup (Block Diagram of Configuration)

Same as described in section 4.2

8.3. Limits and Measurement Result

TOTAL NO. OF	LIMIT (NO. OF CH)	MEASUREMENT (NO. OF CH)	RESULT	
HOPPING CHANNEL	>=15	79	PASS	

TEST PLOT FOR NO. OF TOTAL CHANNELS



Note: The 8-DPSK modulation is the worst case and recorded in the report.

9. Time Of Occupancy (Dwell Time)

9.1. Measurement Procedure

The EUT shall have its hopping function enabled. Use the following spectrum analyzer settings:

- 1. Span: Zero span, centered on a hopping channel.
- 2. RBW shall be ≤ channel spacing and where possible RBW should be set >> 1 / T, where T is the expected dwell time per channel.
- 3. Sweep: As necessary to capture the entire dwell time per hopping channel; where possible use a video trigger and trigger delay so that the transmitted signal starts a little to the right of the start of the plot. The trigger level might need slight adjustment to prevent triggering when the system hops on an adjacent channel; a second plot might be needed with a longer sweep time to show two successive hops on a channel.

Report No.: HK1901210164E

- 4. Detector function: Peak, Trace: Max hold.
- 5. Use the marker-delta function to determine the transmit time per hop.
- 6. Repeat the measurement using a longer sweep time to determine the number of hops over the period specified in the requirements. The sweep time shall be equal to, or less than, the period specified in the requirements. Determine the number of hops over the sweep time and calculate the total number of hops in the period specified in the requirements, using the following equation:

(Number of hops in the period specified in the requirements) = (number of hops on spectrum analyzer) \times (period specified in the requirements / analyzer sweep time)

7. The average time of occupancy is calculated from the transmit time per hop multiplied by the number of hops in the period specified in the requirements.

9.2. Test Setup (Block Diagram of Configuration)

Same as described in section 4.2

9.3. Limits and Measurement Result

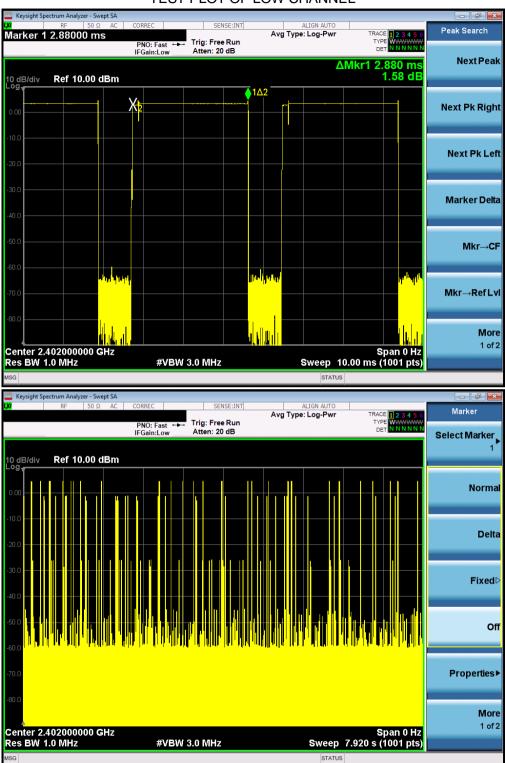
Channel	Time of Pulse for DH5 (ms)	Number of hops in the period specified in the requirements	Sweep Time (ms)	Limit (ms)
Low	2.880	26*4	299.520	400
Middle	2.880	26*4	299.520	400
High	2.900	26*4	301.600	400

Note: The 8-DPSK modulation is the worst case and recorded in the report.



TEST PLOT OF LOW CHANNEL

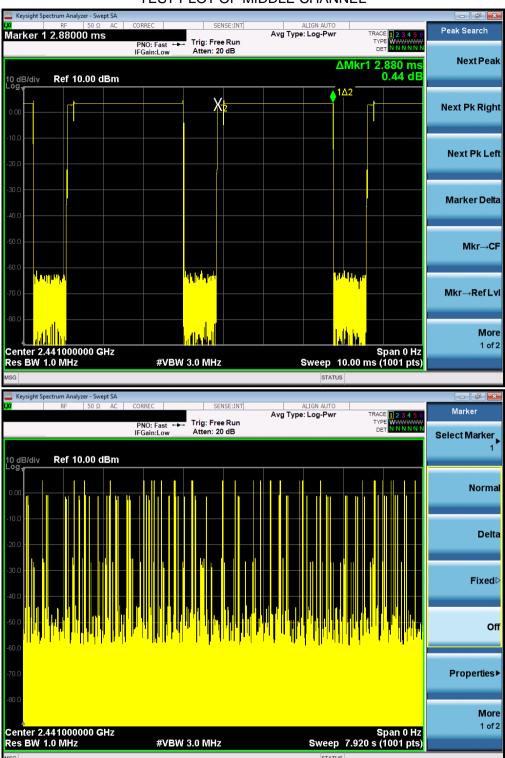
Report No.: HK1901210164E



Report No.: HK1901210164E



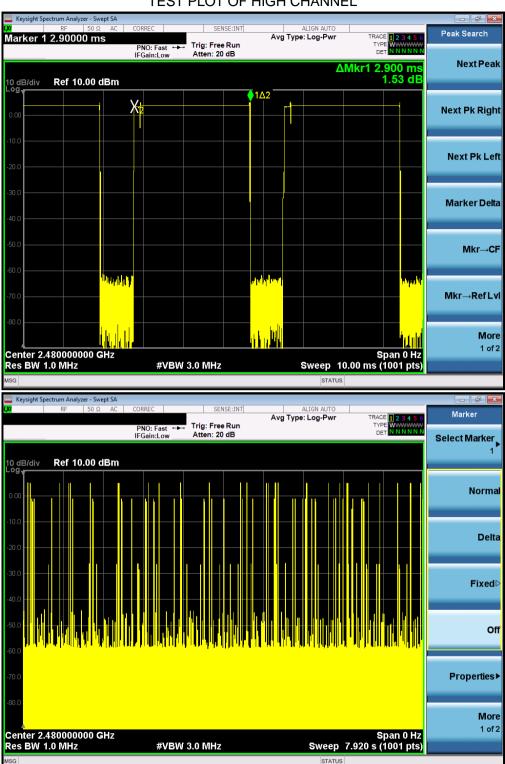
TEST PLOT OF MIDDLE CHANNEL





TEST PLOT OF HIGH CHANNEL

Report No.: HK1901210164E







10. Frequency Separation

10.1.Measurement Procedure

The EUT shall have its hopping function enabled. Use the following spectrum analyzer settings:

- 1. Span: Wide enough to capture the peaks of two adjacent channels.
- 2. RBW: Start with the RBW set to approximately 30% of the channel spacing; adjust as necessary to best identify the center of each individual channel.

Report No.: HK1901210164E

- 3. Video (or average) bandwidth (VBW) ≥ RBW.
- 4. Sweep: Auto. e) Detector function: Peak. f) Trace: Max hold. g) Allow the trace to stabilize. Use the marker-delta function to determine the separation between the peaks of the adjacent channels.

10.2. Test Setup (Block Diagram of Configuration)

Same as described in section 4.2

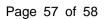
10.3. Limits and Measurement Result

CHANNEL	CHANNEL SEPARATION	LIMIT	RESULT	
	KHz	KHz	Daga	
CH01-CH02 1000		>=25 KHz or 2/3 20 dB BW	Pass	

TEST PLOT FOR FREQUENCY SEPARATION



Note: The 8-DPSK modulation is the worst case and recorded in the report.



Report No.: HK1901210164E



11. Test Setup Photos of the EUT





Page 58 of 58 Report No.: HK1901210164E

Conducted Emission



----END OF REPORT----